

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: Kazuyoshi Okawa, et al.

Serial No.: 10/588,636

Filing Date: August 4, 2006

Title: Semiconductor Device Test  
Apparatus and Method

Conf. No. 9797

Examiner: Daniel F. McMahon

Art Unit: 2117

June 30, 2009  
San Francisco, California

Commissioner of Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**RESPONSE TO OFFICE ACTION**

Sir:

This communication is submitted in response to the office action mailed March 31, 2009  
(referred to herein as "Office Action").